

<b>Notice of References Cited</b>	Application/Control No. 10/814,914		Applicant(s)/Patent Under Reexamination ROBINSON ET AL.	
	Examiner Anil Khatri		Art Unit 2191	Page 1 of 1

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*	C	US-6,998,012	02-2006	Koelliker et al.	156/344
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	V	Smallen et al, "The inca test harness and reporting framework", IEEE, pp 1-10, 2004
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\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.